

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		10/712,762	HEINE ET AL.	
Examiner		Art Unit	Mark Ruthkosky	1745

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	L	US-			
	M	US-			

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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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